



Reg. No. :

Name :

Third Semester B. Tech. Degree Examination, September 2014
(2008 Scheme)
(Special Supplementary)
08.302 : SOLID STATE DEVICES (TA)

Time : 3 Hours

Max. Marks : 100

PART – A

Answer **all** questions briefly. **Each** carries **4** marks.

1. Explain how does the Fermi level position vary with doping in a semiconductor.
2. How are crystal plane and directions designated ?
3. List the assumptions made in the derivation of ideal diode current equation.
4. Define the basic properties of metal-semiconductor junction. Explain the working of a diode, based on this principle.
5. What is meant by carrier life time ? How does it affect the performance of a device ?
6. Sketch the :
 - i) space -charge region
 - ii) charge density
 - iii) electric field and
 - iv) barrier voltage for a P⁺N junction.
7. Why NPN transistors are preferred over PNP transistors ? Explain.
8. How FET can be used as a variable resistor ? Explain.
9. Explain sub-threshold conduction in MOSFET.
10. Draw and explain CV diagram of a MOS capacitor. **(10×4=40 Marks)**





PART – B

Answer **any two** full questions from **each** Module. **Each** full question carries **10** marks.

Module – I

11. a) For a GaAs P⁺N one-sided abrupt junction with $N_D = 8 \times 10^{14}/\text{cc}$, calculate the depletion width at breakdown, if $V_{BR} = 500$ V. Given $\epsilon_r = 12.4$, $\epsilon_0 = 8.85 \times 10^{-14}$ F/cm².
- b) Derive expression for the total current in a semiconductor. Discuss the effect of temperature on total current.
12. a) The resistivity ρ_0 of a Germanium sample is measured at 300 K. The sample is then remelted and doped with 4×10^{16} arsenic atoms per cc. The new crystal has a resistivity of $0.1 \Omega \text{ cm}$ and is n-type. Determine the type and concentration of dopant atoms in the original sample and the value of ρ_0 . Assume $\mu_n = 2\mu_p = 3000 \text{ cm}^2/\text{V-S}$.
- b) Calculate the contact potential of a PN junction diode having $N_A = 10^{17}/\text{cc}$, $N_D = 10^{13}/\text{cc}$ at 30°C . Given $n_i = 1.6 \times 10^{10}/\text{cc}$.
13. a) Derive the expressions for the conductivity of both intrinsic and extrinsic semiconductors.
- b) The mobility of free electrons and holes in Ge are 3800 and 1900 $\text{cm}^2/\text{V-S}$. For Si, they are 1300 and 550 $\text{cm}^2/\text{V-S}$ respectively. Determine the values of intrinsic conductivity of Ge and Si. Take $n_i = 2.5 \times 10^{13}/\text{cc}$ for Ge and $n_i = 1.5 \times 10^{10}/\text{cc}$ for Si at 30°C .

Module – II

14. A Schottky barrier is formed from n-type Si having a doping of $10^{16}/\text{cc}$ and area 10^{-3} cm^2 . A Si pn junction has same area and $N_A = 10^{19}$, $N_D = 10^{16}$, $\tau_p = \tau_n = 1 \mu\text{s}$.
- a) Calculate the Schottky barrier diode current at 0.4 V and 300 K.
- b) Calculate the equilibrium depletion layer capacitance C_j and storage capacitance C_s at 0.4 V forward bias for Schottky diodes. Electron affinity of Si is 4.15 eV, metal work function is 4.9 eV, $B = 100 \text{ A/K}^2 \text{ cm}^2$, $D_{pn} = 12 \text{ cm}^2/\text{s}$, $A = 10^{-3}$, $Q = 1.6 \times 10^{-19} \text{ C}$, $L_{pn} = 3.46 \times 10^{-3} \text{ cm}$, $n_i = 1.5 \times 10^{10}/\text{cm}$, $\epsilon = 18.854 \times 10^{-14}$.



15. a) Establishing appropriate relations, explain why BV_{CBO} is larger than BV_{CEO} .
- b) Compute δ , α , β , I_{CBO} and I_{CEO} of a PNP BJT having $I_{EP} = 2\text{mA}$, $I_{EN} = 0.02\text{mA}$, $I_{cp} = 1.98\text{mA}$ and $I_{cn} = 0.002\text{mA}$.
16. A symmetrical Silicon P^+nP^+ BJT has $A = 10^{-4}\text{cm}^2$, $W_B = 1\mu\text{m}$. Its emitter has $N_A = 10^{17}/\text{cc}$, $\tau_n = 0.1\mu\text{s}$, $\mu_p = 200\text{cm}^2/\text{V-S}$, $\mu_n = 700\text{cm}^2/\text{V-S}$. The base has $N_D = 10^{15}/\text{cc}$, $\tau_p = 10\mu\text{s}$, $\mu_n = 1300\text{cm}^2/\text{V-S}$, $\mu_p = 450\text{cm}^2/\text{V-S}$. Calculate
- a) I_{ES} , I_{CS}
- b) I_B when $V_{EB} = 0.4\text{V}$ and $V_{CB} = -25\text{V}$.



Module – III

17. An Aluminium gate p-channel MOS transistor is made on an n-type silicon substrate with $N_D = 6 \times 10^{16}/\text{cc}$. The SiO_2 thickness is 1000Å in the gate region and the effective interface charge Q_i is $2 \times 10^{11}\text{qc}/\text{cm}^2$. Find the maximum width of depletion layer, the flat band voltage and the threshold voltage.
18. An n-channel silicon JFET has $N_A = 10^{19}/\text{cc}$, $N_D = 10^{15}/\text{cc}$ and $a = 4\mu\text{m}$. Determine at 300 K.
- a) Pinch-off voltage and
- b) The gate bias required to make the thickness of undepleted channel equal to $1\mu\text{m}$ with $V_{DS} = 0$.
19. Neatly sketch the constructional diagram and characteristics of IGBT and explain its working. Compare and contrast its performance with BJT.

(3×2×10=60 Marks)